

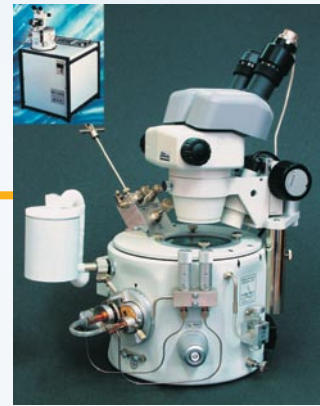
## Unique Sample Preparation Process for Electron Microscopy



**Technoorg Linda** offers a complete set of sample preparation tools for electron microscopy, developed for the field of nanotechnology, materials and semiconductors science, from precise sectioning and polishing through effective ion milling to high quality end-polishing.

Our devices in **Technoorg Linda** are developed for full versatility, high accuracy and flexibility, and can be installed in any sample preparation system. Specimen prepared in other top-of-the-art mechanical or high-energy ion milling systems are compatible with our devices at any stage of the sample preparation process.

**MICROSAW™, MICROHEAT™** and **MICROPOL™** are small, versatile and precise tools for cutting, gluing and mechanical polishing/dimpling of samples to be studied in the electron microscope

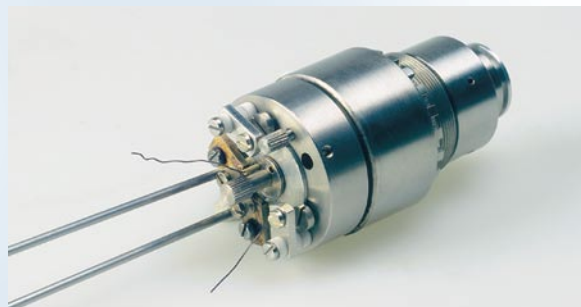


**IV3-IV4 ion mills** are versatile, ultra-high precision devices, capable of solving the most complex tasks of sample preparation. Designed for investigation of special materials, allowing manual setting of all sample preparation parameters in the widest possible range. Available with liquid nitrogen cooling, reactive ion milling and a full variety of ion sources offering effective thinning and final polishing in one.



**GentleMill™ 2 (IV6)** is a fully computer-controlled ion polisher for high-quality final polishing of TEM and XTEM samples and surface cleaning of SEM samples of best quality.

**Technoorg Linda** manufactures top-of-the-art low-energy ion sources that can be practically installed into any device, which requires ion beam technology.



**Mini low-energy ion gun**, a miniaturized ion gun working at extremely low ion energies. Available for high and ultra high vacuum systems. Recommended for special analytical applications.

